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alb	AA	"Merriam Webster's Collegiate Dictionary", 10 th edition, pg 585, Merriam-Webster Incorporated, 1999.								
Qus	AB	Hernandez, Mauricio A., and Salvatore J. Stolfo, "Real-world Data is Dirty: Data Cleansing and the Merge/Purge Problem", Data Mining and Knowledge Discovery, Vol. 2, Issue 1, January 1998.								
QuB	AC	A.F.M. Smith, "A General Bayesian Linear Model," University of Oxford, April 1972.								
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Sheet_1 of 1 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE **DEM1P001** 09/741,958 **APPLICANT** LIST OF DOCUMENTS CIFED BY APPLICANT TO COMPLEWITH 37 CAR. 1.56 **NEAL** DET 0 4 2006 **FILING DATE GROUP** 12/20/00 2623 U.S. PATENT DOCUMENTS DOCUMENT **EXAMINER** DATE NAME **CLASS** SUBCLASS FILING DATE IF INITIAL* NUMBER APPROPRIATE AA 6,684,193 01/27/2004 Chavez et al. 705 6,553,352 04/22/2003 AB Delurgio et al. 400 كە7 AC 6,044,357 03/28/2000 Garg 705 Ø OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) EXAMINER **DATE CONSIDERED** 12/13/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.